



Integrated Device Technology, Inc.

FAST CMOS OCTAL REGISTERED TRANSCIVERS

IDT29FCT52AT/BT/CT
IDT29FCT53AT/BT/CT

FEATURES:

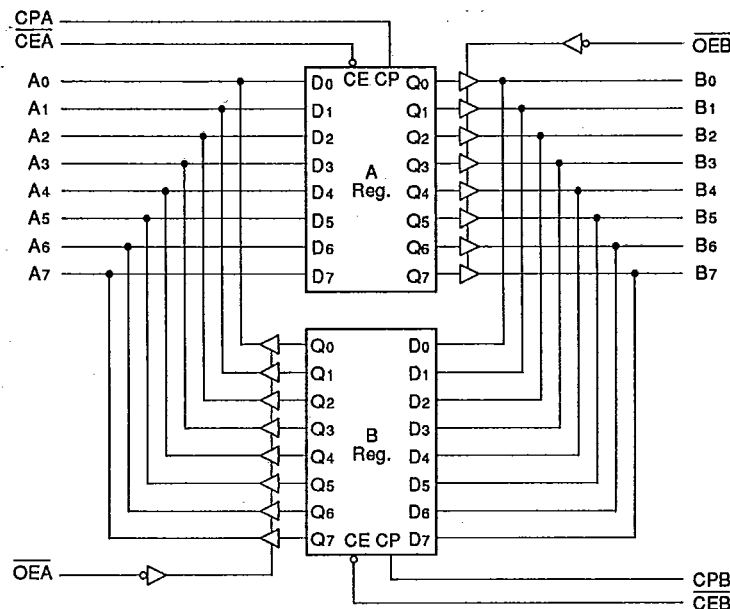
- Equivalent to AMD's Am2952/53 and Fairchild's 29F52/53 in pinout/function
- IDT29FCT52AT/53AT equivalent to FAST™ speed
- IDT29FCT52BT/53BT 25% faster than FAST™
- IDT29FCT52CT/53CT 37% faster than FAST™
- IOL = 64mA (commercial) and 48mA (military)
- CMOS power levels (2.5mW typ. static)
- TTL input and output level compatible
- IOFF feature ideal for hot switching of backplane drivers
- Available in 24-pin DIP, SOIC, 28-pin LCC and PLCC with JEDEC standard pinout
- Product available in Radiation Tolerant and Radiation Enhanced versions
- Military product compliant to MIL-STD-883, Class B

DESCRIPTION:

The IDT29FCT52AT/BT/CT and IDT29FCT53AT/BT/CT are 8-bit registered transceivers manufactured using advanced CEMOS™, a dual metal CMOS technology. Two 8-bit back-to-back registers store data flowing in both directions between two bidirectional buses. Separate clock, clock enable and 3-state output enable signals are provided for each register. Both A outputs and B outputs are guaranteed to sink 64mA.

The IDT29FCT52AT/BT/CT is a non-inverting option of the IDT29FCT53AT/BT/CT.

FUNCTIONAL BLOCK DIAGRAM



NOTE:

1. IDT29FCT52 function is shown.

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FAST is a registered trademark of National Semiconductor Co.

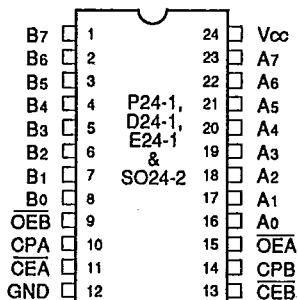
MILITARY AND COMMERCIAL TEMPERATURE RANGES

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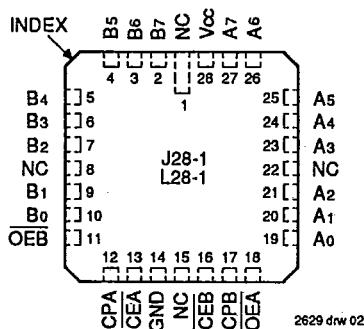
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MILITARY AND COMMERCIAL TEMPERATURE RANGES

PIN CONFIGURATIONS



DIP/CERPACK/SOIC
TOP VIEW



LCC/PLCC
TOP VIEW

PIN DESCRIPTION

Name	I/O	Description
A0-7	I/O	Eight bidirectional lines carrying the A Register inputs or B Register outputs.
B0-7	I/O	Eight bidirectional lines carrying the B Register inputs or A Register outputs.
CPA	I	Clock for the A Register. When $\overline{CEA}$ is LOW, data is entered into the A Register on the LOW-to-HIGH transition of the CPA signal.
$\overline{CEA}$	I	Clock Enable for the A Register. When $\overline{CEA}$ is LOW, data is entered into the A Register on the LOW-to-HIGH transition of the CPA signal. When $\overline{CEA}$ is HIGH, the A Register holds its contents, regardless of CPA signal transitions.
$\overline{OEB}$	I	Output Enable for the A Register. When $\overline{OEB}$ is LOW, the A Register outputs are enabled onto the B0-7 lines. When $\overline{OEB}$ is HIGH, the B0-7 outputs are in the high impedance state.
CPB	I	Clock for the B Register. When $\overline{CEB}$ is LOW, data is entered into the B Register on the LOW-to-HIGH transition of the CPB signal.
$\overline{CEB}$	I	Clock Enable for the B Register. When $\overline{CEB}$ is LOW, data is entered into the B Register on the LOW-to-HIGH transition of the CPB signal. When $\overline{CEB}$ is HIGH, the B Register holds its contents, regardless of CPB signal transitions.
$\overline{OEA}$	I	Output Enable for the B Register. When $\overline{OEA}$ is LOW, the B Register outputs are enabled onto the A0-7 lines. When $\overline{OEA}$ is HIGH, the A0-7 outputs are in the high impedance state.

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REGISTER FUNCTION TABLE⁽¹⁾
(Applies to A or B Register)

Inputs			Internal	Function
D	CP	$\overline{CE}$	Q	
X	X	H	NC	Hold Data
L	↑	L	L	Load Data
H	↑	L	H	

NOTE:

1. H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
NC = No Change
↑ = LOW-to-HIGH Transition

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OUTPUT CONTROL⁽¹⁾

$\overline{OE}$	Internal Q	Y-Outputs		Function
		52	53	
H	X	Z	Z	Disable Outputs
L	L	L	H	Enable Outputs
L	H	H	L	

NOTE:

1. H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
Z = HIGH Impedance

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FAST CMOS OCTAL REGISTERED TRANSCEIVERS

MILITARY AND COMMERCIAL TEMPERATURE RANGES

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Rating	Commercial	Military	Unit
V _{TERM} ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +7.0	-0.5 to +7.0	V
V _{TERM} ⁽³⁾	Terminal Voltage with Respect to GND	-0.5 to V _{CC}	-0.5 to V _{CC}	V
T _A	Operating Temperature	0 to +70	-55 to +125	°C
T _{BIAS}	Temperature Under Bias	-55 to +125	-65 to +135	°C
T _{STG}	Storage Temperature	-55 to +125	-65 to +150	°C
P _T	Power Dissipation	0.5	0.5	W
I _{OUT}	DC Output Current	120	120	mA

CAPACITANCE (T_A = +25°C, f = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V	6	10	pF
C _{I/O}	I/O Capacitance	V _{OUT} = 0V	8	12	pF

NOTE:

1. This parameter is guaranteed by characterization data and not tested.

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NOTES:

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- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed +0.5V unless otherwise noted.
- Inputs and V_{CC} terminals only.
- Outputs and I/O terminals only.

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Commercial: T_A = 0°C to +70°C, V_{CC} = 5.0V ± 5%; Military: T_A = -55°C to +125°C, V_{CC} = 5.0V ± 10%

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
V _{IH}	Input HIGH Level	Guaranteed Logic HIGH Level		2.0	—	—	V
V _{IL}	Input LOW Level	Guaranteed Logic LOW Level		—	—	0.8	V
I _{IH}	Input HIGH Current	V _{CC} = Max., V _I = 2.7V	Except I/O Pins	—	—	5	μA
			I/O Pins	—	—	15	
I _{IL}	Input LOW Current	V _{CC} = Max., V _I = 0.5V	Except I/O Pins	—	—	-5	μA
			I/O Pins	—	—	-15	
I _I	Input HIGH Current	V _{CC} = Max., V _I = V _{CC} (Max.)		—	—	20	μA
V _{IK}	Clamp Diode Voltage	V _{CC} = Min., I _N = -18mA		—	-0.7	-1.2	V
I _{OS}	Short Circuit Current	V _{CC} = Max. ⁽³⁾ , V _O = GND		-60	-120	-225	mA
I _{OFF}	Power Down Disable	V _{CC} = GND, V _O = 4.5V		—	—	100	μA
V _{OH}	Output HIGH Voltage	V _{CC} = Min. V _{IN} = V _{IH} or V _{IL}	I _{OH} = -6mA MIL.	2.4	3.3	—	V
			I _{OH} = -8mA COM'L.				
			I _{OH} = -12mA MIL.	2.0	3.0	—	V
I _{OH} = -15mA COM'L.							
V _{OL}	Output LOW Voltage	V _{CC} = Min. V _{IN} = V _{IH} or V _{IL}	I _{OL} = 48mA MIL. ⁽⁴⁾	—	0.3	0.55	V
			I _{OL} = 64mA COM'L.				
V _H	Input Hysteresis	—		—	200	—	mV
I _{CC}	Quiescent Power Supply Current	V _{CC} = Max. V _{IN} = GND or V _{CC}		—	0.5	1.5	mA

NOTES:

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- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at V_{CC} = 5.0V, +25°C ambient and maximum loading.
- Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.
- These are maximum I_{OL} values per output, for 8 outputs turned on simultaneously. Total maximum I_{OL} (all outputs) is 512mA for commercial and 384mA for military. Derate I_{OL} for number of outputs exceeding 8 turned on simultaneously.

POWER SUPPLY CHARACTERISTICS

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Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
ΔI_{CC}	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$		—	0.5	2.0	mA
I_{CCD}	Dynamic Power Supply Current ⁽⁴⁾	$V_{CC} = \text{Max.}$ Outputs Open $\overline{OE}_A$ or $\overline{OE}_B = \text{GND}$ One Input Toggling 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	0.15	0.25	mA/ MHz
I_C	Total Power Supply Current ⁽⁶⁾	$V_{CC} = \text{Max.}$ Outputs Open $f_{CP} = 10\text{MHz}$ 50% Duty Cycle $\overline{OE}_A$ or $\overline{OE}_B = \text{GND}$ One Bit Toggling at $f_i = 5\text{MHz}$ 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	2.0	4.0	mA
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	2.5	6.0	
		$V_{CC} = \text{Max.}$ Outputs Open $f_{CP} = 10\text{MHz}$ 50% Duty Cycle $\overline{OE}_A$ or $\overline{OE}_B = \text{GND}$ Eight Bits Toggling at $f_i = 2.5\text{MHz}$ 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	4.3	7.8 ⁽⁵⁾	
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	6.5	16.8 ⁽⁵⁾	

NOTES:

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1. For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical values are at $V_{CC} = 5.0V$, $+25^\circ\text{C}$ ambient.3. Per TTL driven input ($V_{IN} = 3.4V$); all other inputs at V_{CC} or GND .

4. This parameter is not directly testable, but is derived for use in Total Power Supply calculations.

5. Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.6. $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$ $I_C = I_{CC} + \Delta I_{CC} D_{HNT} + I_{CCD} (f_{CP}/2 + f_i N_i)$ $I_{CC} = \text{Quiescent Current}$ $\Delta I_{CC} = \text{Power Supply Current for a TTL High Input } (V_{IN} = 3.4V)$ $D_{HNT} = \text{Duty Cycle for TTL Inputs High}$ $N_i = \text{Number of TTL Inputs at } D_H$ $I_{CCD} = \text{Dynamic Current Caused by an Input Transition Pair (HLH or LHL)}$ $f_{CP} = \text{Clock Frequency for Register Devices (Zero for Non-Register Devices)}$ $f_i = \text{Input Frequency}$ $N_i = \text{Number of Inputs at } f_i$

All currents are in milliamperes and all frequencies are in megahertz.

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MILITARY AND COMMERCIAL TEMPERATURE RANGES

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

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Symbol	Parameter	Condition ⁽¹⁾	IDT29FCT52AT/53AT				IDT29FCT52BT/53BT				IDT29FCT52CT/53CT				Unit
			Com'l.		Mil.		Com'l.		Mil.		Com'l.		Mil.		
			Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	
tPLH tPHL	Propagation Delay CPA, CPB to A _n , B _n	CL = 50pF RL = 500Ω	2.0	10.0	2.0	11.0	2.0	7.5	2.0	8.0	2.0	6.3	—	7.3	ns
tPZH tPZL	Output Enable Time OE _A or OE _B to A _n , B _n		1.5	10.5	1.5	13.0	1.5	8.0	1.5	8.5	1.5	7.0	—	8.0	ns
tPHZ tPLZ	Output Disable Time OE _A or OE _B to A _n , B _n		1.5	10.0	1.5	10.0	1.5	7.5	1.5	8.0	1.5	6.5	—	7.5	ns
tSU	Set-up Time HIGH or LOW A _n , B _n to CPA, CPB		2.5	—	2.5	—	2.5	—	2.5	—	2.5	—	2.5	—	ns
tH	Hold Time HIGH or LOW A _n , B _n to CPA, CPB		2.0	—	2.0	—	1.5	—	1.5	—	1.5	—	1.5	—	ns
tSU	Set-up Time HIGH or LOW OE _A , OE _B to CPA, CPB		3.0	—	3.0	—	3.0	—	3.0	—	3.0	—	3.0	—	ns
tH	Hold Time HIGH or LOW OE _A , OE _B to CPA, CPB		2.0	—	2.0	—	2.0	—	2.0	—	2.0	—	2.0	—	ns
tW	Pulse Width HIGH ⁽³⁾ or LOW CPA or CPB		3.0	—	3.0	—	3.0	—	3.0	—	3.0	—	3.0	—	ns

NOTES:

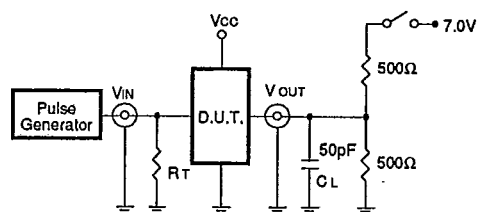
- See test circuit and waveforms.
- Minimum limits are guaranteed but not tested on Propagation Delays.
- This parameter is guaranteed but not tested.

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TEST CIRCUITS AND WAVEFORMS

TEST CIRCUITS FOR ALL OUTPUTS



SWITCH POSITION

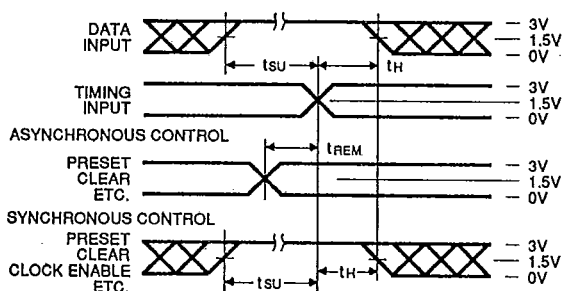
Test	Switch
Open Drain Disable Low Enable Low	Closed
All Other Outputs	Open

DEFINITIONS:

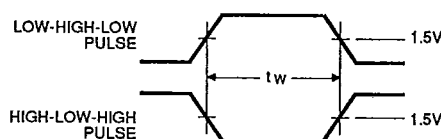
CL = Load capacitance; includes jig and probe capacitance.
RT = Termination resistance: should be equal to Z_{OUT} of the Pulse Generator.

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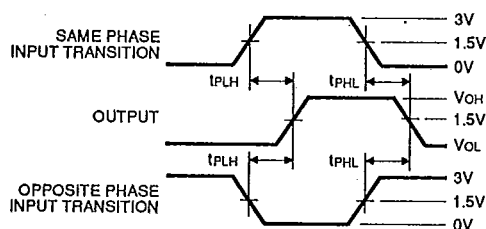
SET-UP, HOLD AND RELEASE TIMES



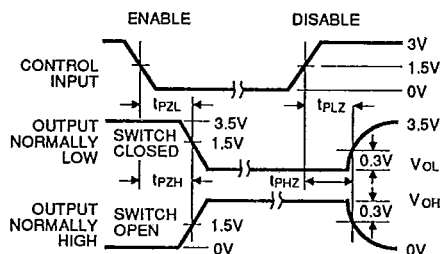
PULSE WIDTH



PROPAGATION DELAY



ENABLE AND DISABLE TIMES



NOTES

- Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
- Pulse Generator for All Pulses: Rate ≤ 1.0 MHz; Z₀ ≤ 50Ω; t_r ≤ 2.5ns; t_r ≤ 2.5ns.

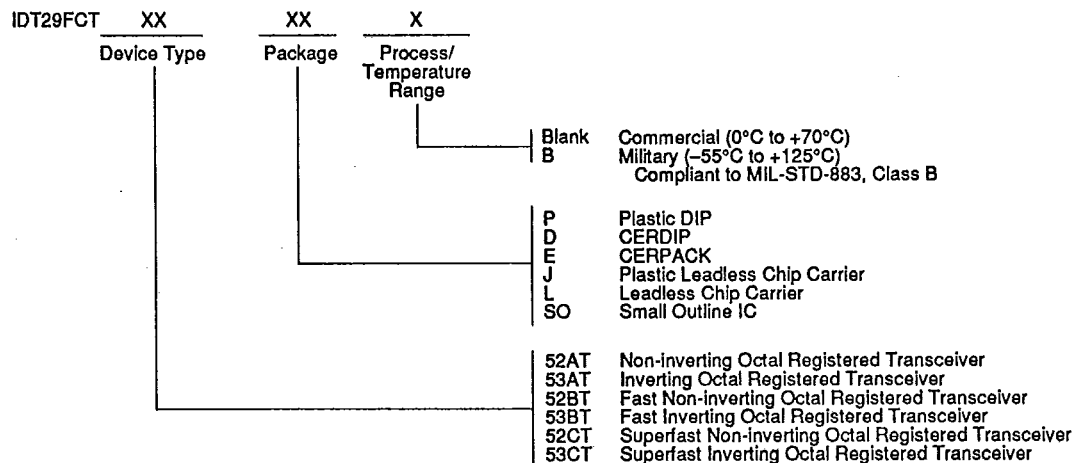
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ORDERING INFORMATION

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